

Analyzing side-channel attack vulnerabilities at RTL

Lai, Xinhui; Jenihhin, Maksim 2023 IEEE 24th Latin American Test Symposium (LATS) 2023 / 2 p. : ill
<https://doi.org/10.1109/LATS58125.2023.10154497>

Approaches to extra-functional verification of security and reliability aspects in hardware designs = Riistvaraprojektide turva- ja töökindlusaspektide ekstrasfunktsionaalse verifitseerimise lähenemisviisid

Lai, Xinhui 2022 <https://doi.org/10.23658/taltech.29/2022> <https://digikogu.taltech.ee/et/Item/cff1aeb9-b0b2-49ce-b81a-bfb9dc25fd56>
https://www.ester.ee/record=b5502807*est

Early RTL analysis for SCA vulnerability in fuzzy extractors of memory-based PUF enabled devices

Lai, Xinhui; Jenihhin, Maksim; Selims, Georgios arXiv.org 2020 / 6 p. : ill <https://doi.org/10.48550/arXiv.2008.08409>
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On antagonism between side-channel security and soft-error reliability in BNN inference engines

Lai, Xinhui; Lange, Thomas; Balakrishnan, Aneesh; Alexandrescu, Dan; Jenihhin, Maksim IFIP/IEEE 29th International Conference on Very Large Scale Integration (VLSI-SoC) 2021 / p. 1-6 <https://doi.org/10.1109/VLSI-SoC53125.2021.9606981>

PASCAL : timing SCA resistant design and verification flow

Lai, Xinhui; Jenihhin, Maksim; Raik, Jaan; Paul, Kolin 2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS 2019) : 1-3 July 2019, Greece 2019 / p. 239-242 : ill <https://doi.org/10.1109/IOLTS.2019.8854458>

RESCUE EDA Toolset for interdependent aspects of reliability, security and quality in nanoelectronic systems design

Gürsoy, Cemil Cem; Cardoso Medeiros, Guilherme; Chen, Juanho; Balakrishnan, Aneesh; Lai, Xinhui; Bagbaba, Ahmet Cagri; Raik, Jaan; Jenihhin, Maksim DATE 2019 2019 / 1 p. : ill <https://doi.org/10.5281/zenodo.3362529> <https://past.date-conference.com/>

Towards multidimensional verification : where functional meets non-functional

Jenihhin, Maksim; Lai, Xinhui; Ghasempouri, Tara; Raik, Jaan 2018 IEEE Nordic Circuits and Systems Conference (NORCAS) : NORCHIP and International Symposium of System-on-Chip (SoC) : 30-31 October 2018, Tallinn, Estonia : proceedings in IEEE Xplore 2018 / 7 p. : ill <https://doi.org/10.1109/NORCHIP.2018.8573495>

Understanding multidimensional verification : where functional meets non-functional

Lai, Xinhui; Balakrishnan, Aneesh; Lange, Thomas; Jenihhin, Maksim; Ghasempouri, Tara; Raik, Jaan; Alexandrescu, Dan Microprocessors and microsystems 2019 / art. 102867, 13 p. : ill <https://doi.org/10.1016/j.micpro.2019.102867> [Journal metrics at Scopus](#)
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